Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	er .
10/575,545	VAN MEJIL	
Examiner	Art Unit	
Hien D. Vu	2833	

	SEARCHED				
Class	Subclass	Date	Examiner		
439	362 364 607 677 953	9/24/07	#V		
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INTERFERENCE SEARCHED					
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